# BLF8G20LS-400PV; BLF8G20LS-400PGV

**Power LDMOS transistor** 

Rev. 4 — 28 July 2015

**Product data sheet** 

### 1. Product profile

### 1.1 General description

400 W LDMOS power transistor with improved video bandwidth for base station applications at frequencies from 1805 MHz to 1995 MHz.

#### Table 1. Typical performance

Typical RF performance at  $T_{case} = 25$  °C in a common source class-AB production test circuit, tested on straight lead device.

Test signal	f	I <sub>Dq</sub>	V <sub>DS</sub>	P <sub>L(AV)</sub>	Gp	ησ	ACPR <sub>5M</sub>
	(MHz)	(mA)	(V)	(W)	(dB)	(%)	(dBc)
2-carrier W-CDMA	1805 to 1995	3400	28	95	19	28	-33 [ <u>1]</u>

[1] Test signal: 3GPP test model 1; 64 DPCH; PAR = 7.5 dB at 0.01 % probability on CCDF; carrier spacing = 5 MHz;  $f_1$  = 1807.5 MHz;  $f_2$  = 1812.5 MHz;  $f_3$  = 1872.5 MHz;  $f_4$  = 1877.5 MHz.

### **1.2 Features and benefits**

- Decoupling leads to enable improved Video BandWidth (VBW) (120 MHz typical)
- High efficiency
- Low thermal resistance providing excellent thermal stability
- Designed for broadband operation
- Lower output capacitance for improved performance in Doherty applications
- Designed for low memory effects providing excellent pre-distortability
- Internally matched for ease of use
- Integrated ESD protection
- Design optimized for gull-wing
- Excellent ruggedness
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

### **1.3 Applications**

 RF power amplifiers for base stations and multi carrier applications in the 1805 MHz to 1995 MHz frequency range



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### 2. Pinning information

Table 2. Pi	nning		
Pin	Description	Simplified outline	Graphic symbol
BLF8G20LS-	400PV (SOT1242B)		
1	drain1		
2	drain2		6
3	gate1		8-
4	gate2		3
5	source [1]		4
6	decoupling1	5	9•
7	decoupling2		~7
8	n.c.		aaa-007816
9	n.c.		
BLF8G20LS-	400PGV (SOT1242C)		
1	drain1	6 1 2 7	1
2	drain2		6
3	gate1		8
4	gate2		3
5	source [1]	8 3 4 9 5	4
6	decoupling1		9•  <b>F</b>
7	decoupling2		~7
8	n.c.		aaa-007816
9	n.c.		

[1] Connected to flange.

### 3. Ordering information

#### Table 3.Ordering information

Type number	Packag	Package				
	Name	Description	Version			
BLF8G20LS-400PV	-	earless flanged ceramic package; 8 leads	SOT1242B			
BLF8G20LS-400PGV	-	earless flanged ceramic package; 8 leads	SOT1242C			

### 4. Limiting values

#### Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Мах	Unit
V <sub>DS</sub>	drain-source voltage		-	65	V
V <sub>GS</sub>	gate-source voltage		-0.5	+13	V
T <sub>stg</sub>	storage temperature		-65	+150	°C
Тj	junction temperature	[1]	-	225	°C

[1] Continuous use at maximum temperature will affect the reliability, for details refer to the on-line MTF calculator.

### 5. Thermal characteristics

Table 5.	Thermal characteristics					
Symbol	Parameter	Conditions	Тур	Unit		
R <sub>th(j-c)</sub>	thermal resistance from junction to case	$T_{case} = 80 \ ^{\circ}C; P_{L} = 80 \ W$	0.23	K/W		

### 6. Characteristics

#### Table 6. DC characteristics

 $T_i = 25$  °C; per section unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>(BR)DSS</sub>	drain-source breakdown voltage	$V_{GS} = 0 V; I_D = 3.0 mA$	65	-	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	V <sub>DS</sub> = 10 V; I <sub>D</sub> = 300 mA	1.5	1.9	2.3	V
I <sub>DSS</sub>	drain leakage current	$V_{GS} = 0 V; V_{DS} = 28 V$	-	-	3.0	μA
I <sub>DSX</sub>	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 V;$ $V_{DS} = 10 V$		51.5	-	A
I <sub>GSS</sub>	gate leakage current	$V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	300	nA
9 <sub>fs</sub>	forward transconductance	V <sub>DS</sub> = 10 V; I <sub>D</sub> = 15 A	-	20.6	-	S
R <sub>DS(on)</sub>	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 V;$ I <sub>D</sub> = 10.5 A	-	0.055	-	Ω

#### Table 7.RF characteristics

Test signal: 2-carrier W-CDMA; PAR = 7.5 dB at 0.01 % probability on the CCDF; 3GPP test model 1; 1-64 DPCH;  $f_1$  = 1807.5 MHz;  $f_2$  = 1812.5 MHz;  $f_3$  = 1872.5 MHz;  $f_4$  = 1877.5 MHz; RF performance at  $V_{DS}$  = 28 V;  $I_{Dq}$  = 3400 mA;  $T_{case}$  = 25 °C; unless otherwise specified; in a class-AB production test circuit, tested on straight lead device.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
G <sub>p</sub>	power gain	$P_{L(AV)} = 95 W$	17.8	19	-	dB
RL <sub>in</sub>	input return loss	$P_{L(AV)} = 95 W$	-	-12	-6	dB
$\eta_D$	drain efficiency	$P_{L(AV)} = 95 W$	24	28	-	%
$ACPR_{5M}$	adjacent channel power ratio (5 MHz)	$P_{L(AV)} = 95 W$	-	-33	-28	dBc

### 7. Test information

### 7.1 Ruggedness in class-AB operation

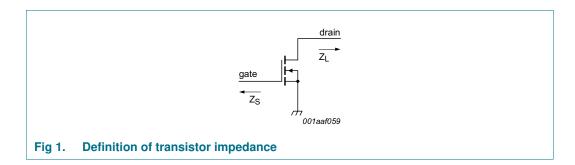
The BLF8G20LS-400PV and BLF8G20LS-400PGV are capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions:  $V_{DS} = 28 \text{ V}$ ;  $I_{Dq} = 3300 \text{ mA}$ ; 2-carrier W-CDMA signal;  $P_L = 200 \text{ W}$ ;  $f_c = 1800 \text{ MHz}$ ; 5 MHz spacing, 46 % clipping.

### 7.2 Impedance information

Table 8.	Typical impedance for the top-half of the push-pull package
Measured	load-pull data; $I_{Dq} = 1800 \text{ mA}$ ; $V_{DS} = 28 \text{ V}$ ; $T_{case} = 25 \text{ °C}$ , water cooled.

f	Z <sub>S</sub> [1]	Z <sub>L</sub> [1]
(MHz)	(Ω)	(Ω)
BLF8G20LS-400PV (straight le	ead)	
1800	4.1 – j4.66	4.1 – j4.5
1840	5.2 – j3.6	4.4 – j4.4
1880	4.6 – j1.45	4.85 – j4.25
1930	2.8 – j0.3	4.5 – j4.3
1960	2.1 – j0.5	5.5 – j3.5
1990	1.56 – j0.6	5.5 – j3.4
BLF8G20LS-400PGV (gull-win	g)	
1800	3.7 – j7.6	4.2 – j6.8
1840	4.34 – j6.1	4.4 – j6.7
1880	4.75 – j5.2	4 – j6.4
1930	3.17 – j3.4	4.6 – j6.5
1960	2 – j3.05	5.8 – j5.5
1990	2.5 – j2.6	5.8– j5.7

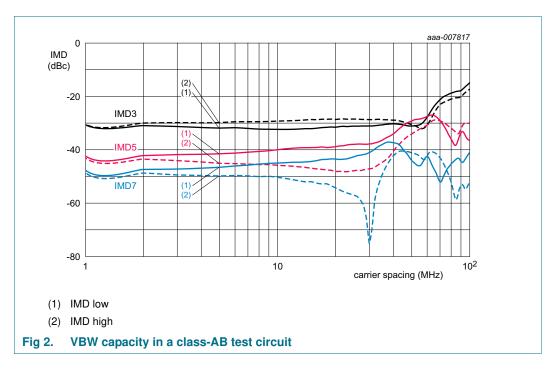
[1]  $Z_S$  and  $Z_L$  defined in Figure 1.



### 7.3 VBW in class-AB operation

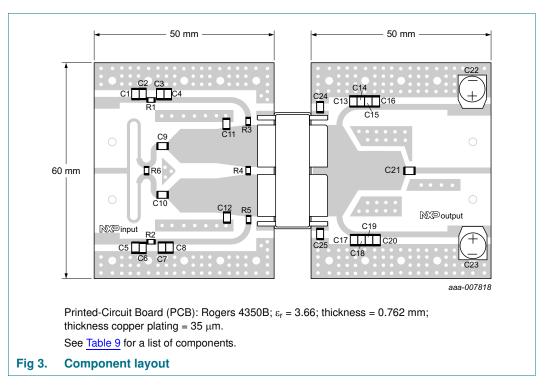
The BLF8G20LS-400PV and BLF8G20LS-400PGV have a video bandwidth of 120 MHz (typical) when measured in a class-AB test circuit operating in the 1800 MHz to 1880 MHz frequency band for  $V_{DS} = 28$  V and  $I_{Dq} = 3.3$  A, where the VBW is defined as the location of the resonance in the base-band impedance measurement obtained using a low-frequency probe.

The VBW measurement based on the 2-tone IMD test as a function of carrier spacing is shown below.



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### 7.4 Test circuit



### Table 9. List of components

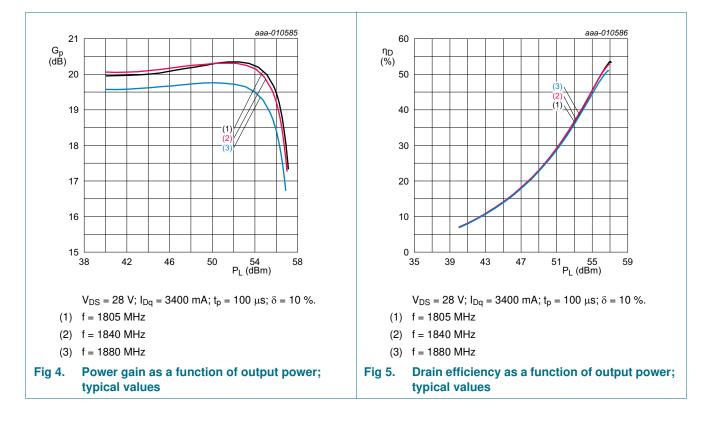
See Figure 3 for component layout.

Component	Description	Value	Remarks
C1, C5, C16, C20	multilayer ceramic chip capacitor	10 μF, 50 V	Murata, SMD 2220
C2, C6, C15, C19, C24, C25	multilayer ceramic chip capacitor	4.7 μF, 50 V	Murata
C3, C7, C14, C18	multilayer ceramic chip capacitor	1 nF	ATC100B
C4, C8, C9, C10, C13, C17, C21	multilayer ceramic chip capacitor	24 pF	ATC100B
C11, C12	multilayer ceramic chip capacitor	100 pF	ATC100B
C22, C23	electrolytic capacitor	2200 μF, 63 V	
R1, R2	resistor	10 Ω	SMD 1206
R3, R5	resistor	5.1 Ω	SMD 1206
R4	resistor	33 Ω	SMD 1206
R6	resistor	100 Ω	SMD 1206

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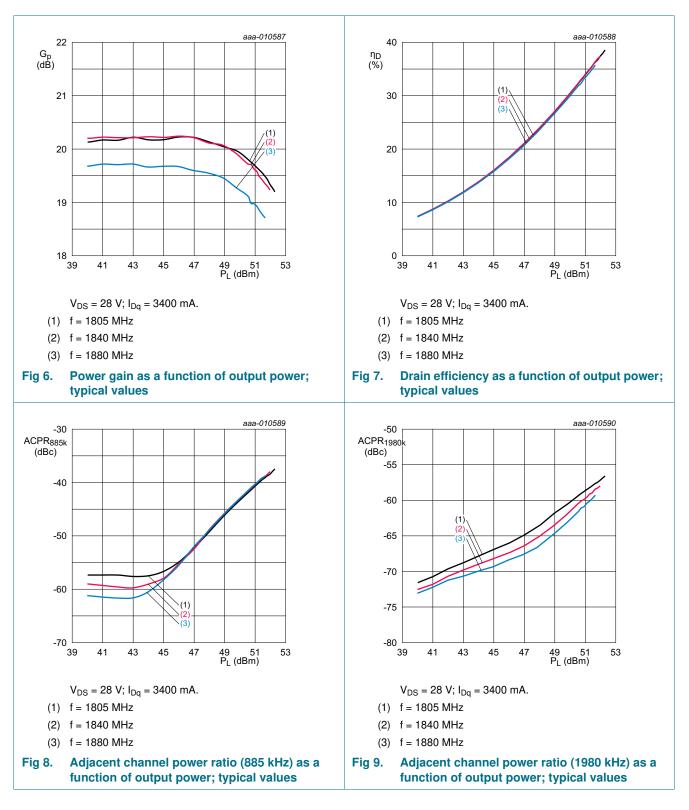


### 7.5.1 Pulsed CW



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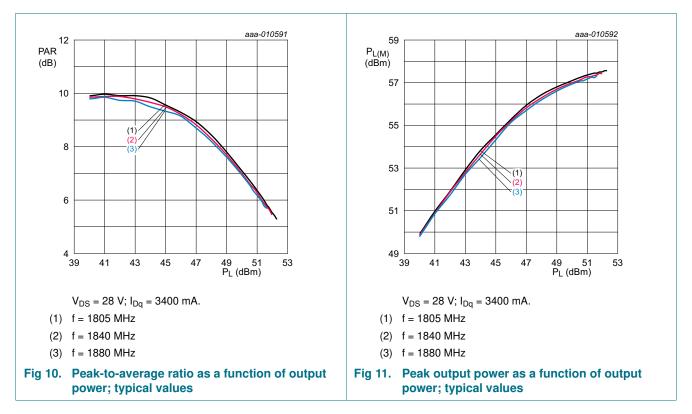




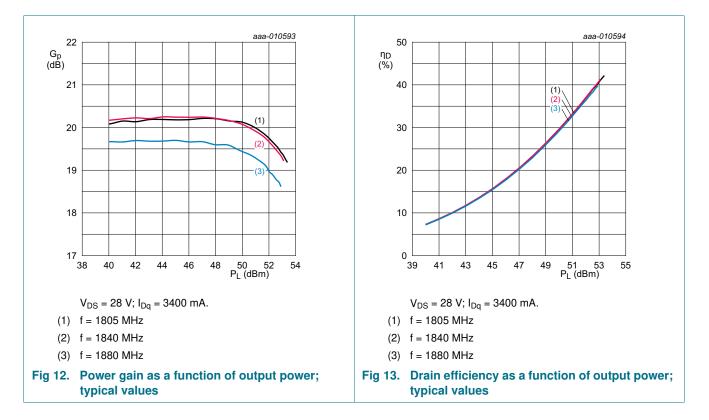
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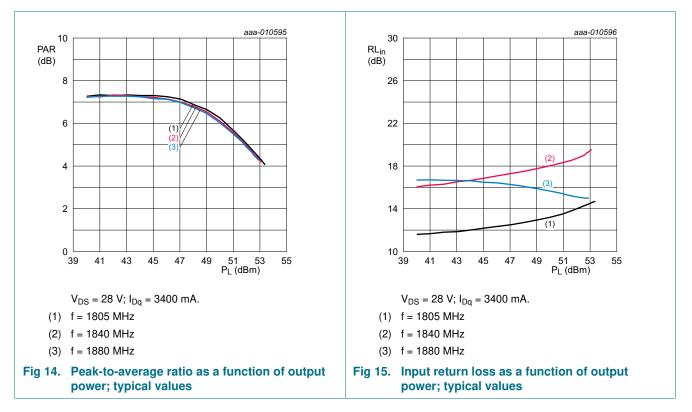
### 7.5.3 1-Carrier W-CDMA



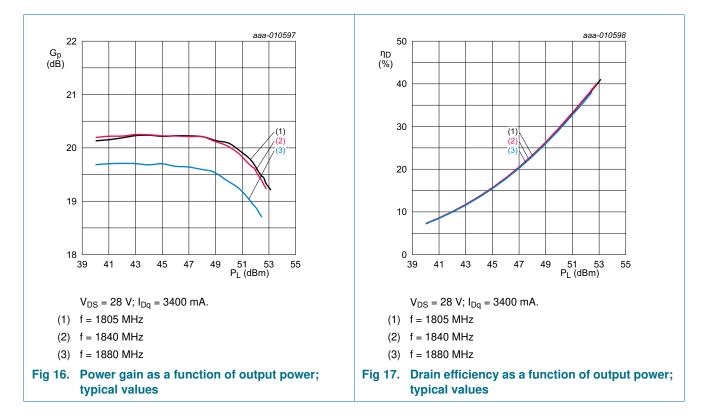
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# BLF8G20LS-400P(G)V

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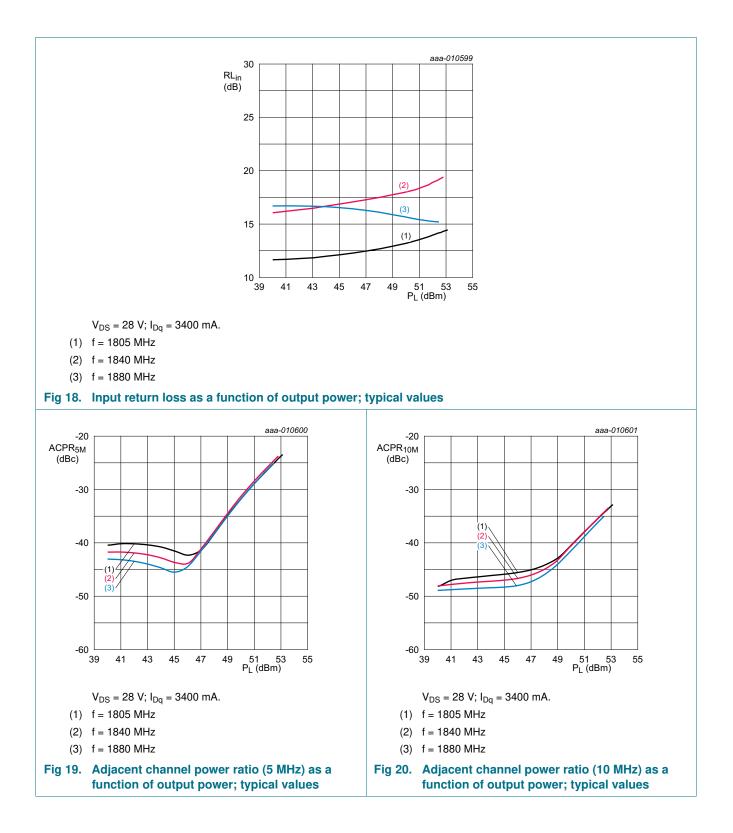
### 7.5.4 2-Carrier W-CDMA



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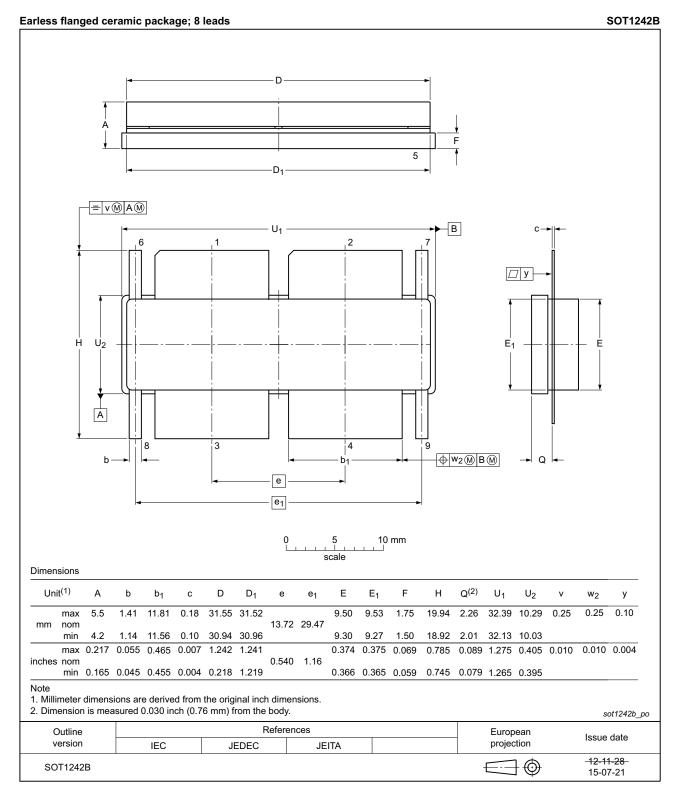
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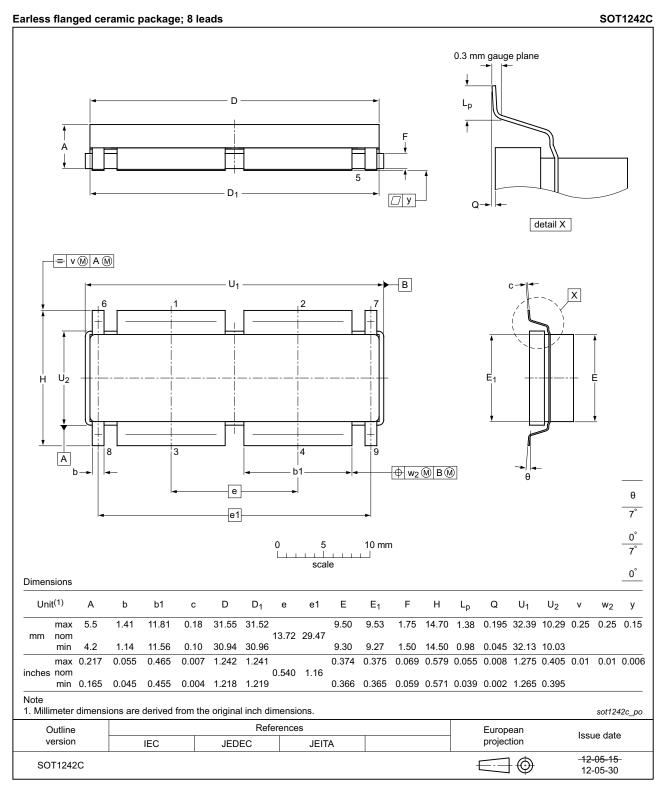
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#### **Package outline** 8.



#### Fig 21. Package outline SOT1242B

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#### Fig 22. Package outline SOT1242C

BLF8G20LS-400PV\_LS-400PGV
Product data sheet

### 9. Handling information

### CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

### **10. Abbreviations**

Table 10. Abbre	Table 10. Abbreviations				
Acronym	Description				
3GPP	3rd Generation Partnership Project				
CCDF	Complementary Cumulative Distribution Function				
CW	Continuous Wave				
DPCH	Dedicated Physical Channel				
ESD	ElectroStatic Discharge				
IMD	InterModulation Distortion				
IS-95	Interim Standard 95				
LDMOS	Laterally Diffused Metal Oxide Semiconductor				
MTF	Median Time to Failure				
PAR	Peak-to-Average Ratio				
SMD	Surface Mounted Device				
VSWR	Voltage Standing Wave Ratio				
W-CDMA	Wideband Code Division Multiple Access				

### **11. Revision history**

#### Table 11.Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF8G20LS-400PV_LS-400PGV v.4	20150728	Product data sheet	-	BLF8G20LS-400PV _LS-400PGV v.3
Modifications	Figure Fig	21. on page 12: This figure	e has been update	d
BLF8G20LS-400PV_LS-400PGV v.3	20140603	Product data sheet	-	BLF8G20LS-400PV _LS-400PGV v.2
BLF8G20LS-400PV_LS-400PGV v.2	20130625	Product data sheet	-	BLF8G20LS-400PV _LS-400PGV v.1
BLF8G20LS-400PV_LS-400PGV v.1	20130606	Preliminary data sheet	-	-

BLF8G20LS-400PV\_LS-400PGV

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Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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